

<b>Notice of References Cited</b>	Application/Control No. 10/724,894	Applicant(s)/Patent Under Reexamination KONNO ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-5,663,755	09-1997	Wada et al.	347/176
*	D	US-4,940,412	07-1990	Blumenthal, Rafael	434/267
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	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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